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### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### Applications of Embedded - CPLDs

#### Details

Product Status	Obsolete
Programmable Type	EE PLD
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	84
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/epm7128eqc100-15">https://www.e-xfl.com/product-detail/intel/epm7128eqc100-15</a>

**Table 2. MAX 7000S Device Features**

Feature	EPM7032S	EPM7064S	EPM7128S	EPM7160S	EPM7192S	EPM7256S
Usable gates	600	1,250	2,500	3,200	3,750	5,000
Macrocells	32	64	128	160	192	256
Logic array blocks	2	4	8	10	12	16
Maximum user I/O pins	36	68	100	104	124	164
$t_{PD}$ (ns)	5	5	6	6	7.5	7.5
$t_{SU}$ (ns)	2.9	2.9	3.4	3.4	4.1	3.9
$t_{FSU}$ (ns)	2.5	2.5	2.5	2.5	3	3
$t_{CO1}$ (ns)	3.2	3.2	4	3.9	4.7	4.7
$f_{CNT}$ (MHz)	175.4	175.4	147.1	149.3	125.0	128.2

## ...and More Features

- Open-drain output option in MAX 7000S devices
- Programmable macrocell flipflops with individual clear, preset, clock, and clock enable controls
- Programmable power-saving mode for a reduction of over 50% in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- 44 to 208 pins available in plastic J-lead chip carrier (PLCC), ceramic pin-grid array (PGA), plastic quad flat pack (PQFP), power quad flat pack (RQFP), and 1.0-mm thin quad flat pack (TQFP) packages
- Programmable security bit for protection of proprietary designs
- 3.3-V or 5.0-V operation
  - MultiVolt™ I/O interface operation, allowing devices to interface with 3.3-V or 5.0-V devices (MultiVolt I/O operation is not available in 44-pin packages)
  - Pin compatible with low-voltage MAX 7000A and MAX 7000B devices
- Enhanced features available in MAX 7000E and MAX 7000S devices
  - Six pin- or logic-driven output enable signals
  - Two global clock signals with optional inversion
  - Enhanced interconnect resources for improved routability
  - Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
  - Programmable output slew-rate control
- Software design support and automatic place-and-route provided by Altera's development system for Windows-based PCs and Sun SPARCstation, and HP 9000 Series 700/800 workstations

The MAX 7000 architecture supports 100% TTL emulation and high-density integration of SSI, MSI, and LSI logic functions. The MAX 7000 architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 7000 devices are available in a wide range of packages, including PLCC, PGA, PQFP, RQFP, and TQFP packages. See [Table 5](#).

**Table 5. MAX 7000 Maximum User I/O Pins** *Note (1)*

Device	44-Pin PLCC	44-Pin PQFP	44-Pin TQFP	68-Pin PLCC	84-Pin PLCC	100-Pin PQFP	100-Pin TQFP	160-Pin PQFP	160-Pin PGA	192-Pin PGA	208-Pin PQFP	208-Pin RQFP
EPM7032	36	36	36									
EPM7032S	36		36									
EPM7064	36		36	52	68	68						
EPM7064S	36		36		68	68						
EPM7096				52	64	76						
EPM7128E					68	84		100				
EPM7128S					68	84	84 (2)	100				
EPM7160E					64	84		104				
EPM7160S					64		84 (2)	104				
EPM7192E								124	124			
EPM7192S								124				
EPM7256E								132 (2)		164		164
EPM7256S											164 (2)	164

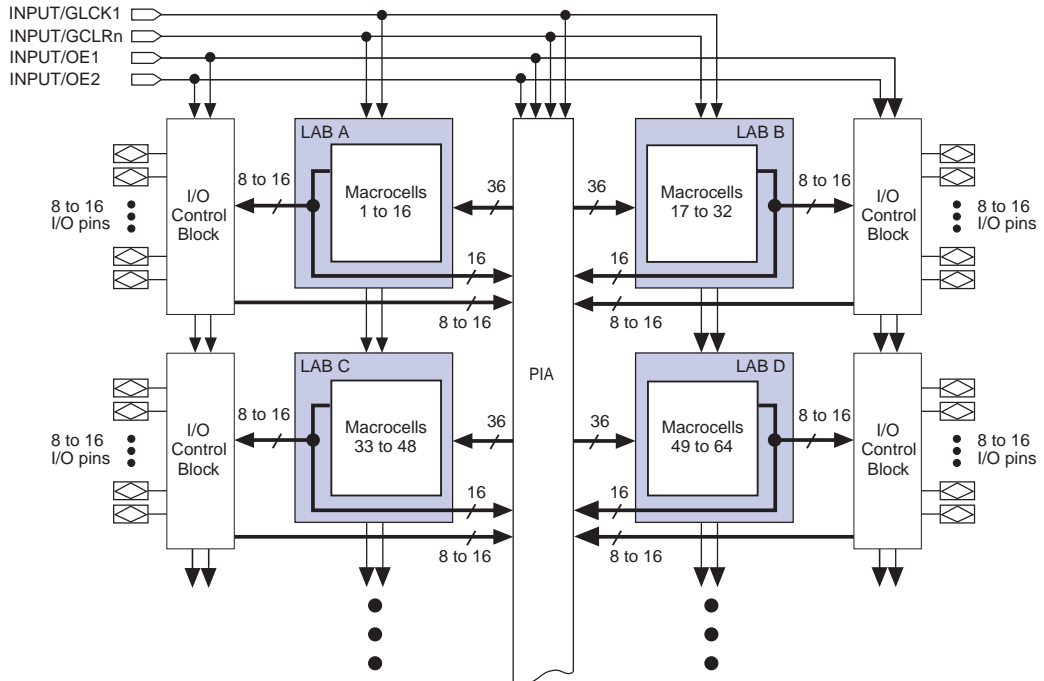
**Notes:**

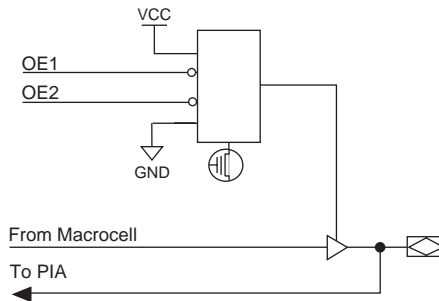
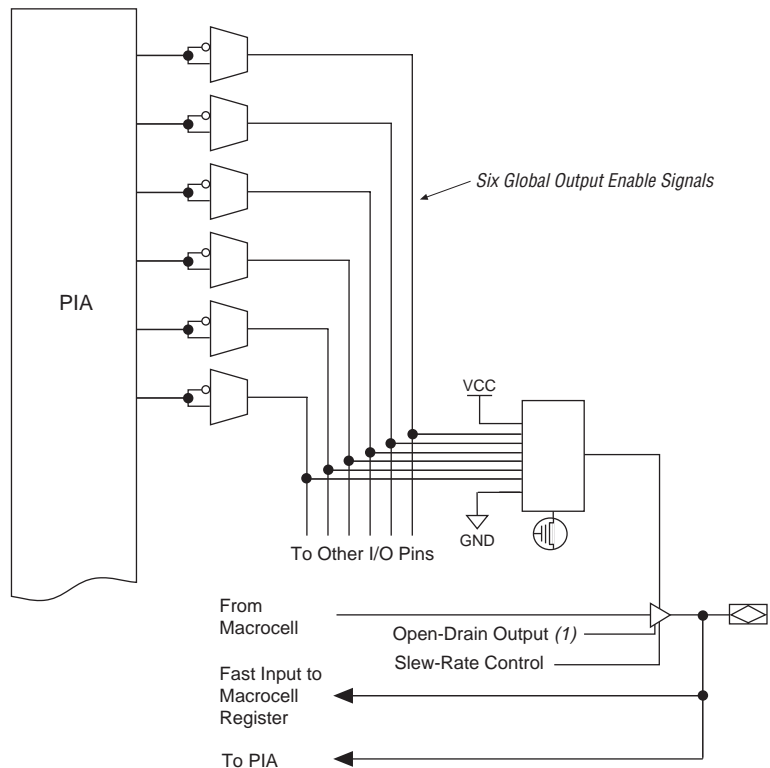
- (1) When the JTAG interface in MAX 7000S devices is used for either boundary-scan testing or for ISP, four I/O pins become JTAG pins.
- (2) Perform a complete thermal analysis before committing a design to this device package. For more information, see the [Operating Requirements for Altera Devices Data Sheet](#).

MAX 7000 devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000 architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

The MAX 7000 architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. Figure 1 shows the architecture of EPM7032, EPM7064, and EPM7096 devices.

**Figure 1. EPM7032, EPM7064 & EPM7096 Device Block Diagram**



**Figure 8. I/O Control Block of MAX 7000 Devices****EPM7032, EPM7064 & EPM7096 Devices****MAX 7000E & MAX 7000S Devices****Note:**

- (1) The open-drain output option is available only in MAX 7000S devices.

When the tri-state buffer control is connected to ground, the output is tri-stated (high impedance) and the I/O pin can be used as a dedicated input. When the tri-state buffer control is connected to  $V_{CC}$ , the output is enabled.

The MAX 7000 architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

## **In-System Programmability (ISP)**

MAX 7000S devices are in-system programmable via an industry-standard 4-pin Joint Test Action Group (JTAG) interface (IEEE Std. 1149.1-1990). ISP allows quick, efficient iterations during design development and debugging cycles. The MAX 7000S architecture internally generates the high programming voltage required to program EEPROM cells, allowing in-system programming with only a single 5.0 V power supply. During in-system programming, the I/O pins are tri-stated and pulled-up to eliminate board conflicts. The pull-up value is nominally 50 k $\Omega$ .

ISP simplifies the manufacturing flow by allowing devices to be mounted on a printed circuit board with standard in-circuit test equipment before they are programmed. MAX 7000S devices can be programmed by downloading the information via in-circuit testers (ICT), embedded processors, or the Altera MasterBlaster, ByteBlasterMV, ByteBlaster, BitBlaster download cables. (The ByteBlaster cable is obsolete and is replaced by the ByteBlasterMV cable, which can program and configure 2.5-V, 3.3-V, and 5.0-V devices.) Programming the devices after they are placed on the board eliminates lead damage on high-pin-count packages (e.g., QFP packages) due to device handling and allows devices to be reprogrammed after a system has already shipped to the field. For example, product upgrades can be performed in the field via software or modem.

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. Because some in-circuit testers cannot support an adaptive algorithm, Altera offers devices tested with a constant algorithm. Devices tested to the constant algorithm have an "F" suffix in the ordering code.

The Jam<sup>TM</sup> Standard Test and Programming Language (STAPL) can be used to program MAX 7000S devices with in-circuit testers, PCs, or embedded processor.

The programming times described in [Tables 6 through 8](#) are associated with the worst-case method using the enhanced ISP algorithm.

**Table 6. MAX 7000S  $t_{PULSE}$  &  $Cycle_{TCK}$  Values**

Device	Programming		Stand-Alone Verification	
	$t_{PULSE}$ (s)	$Cycle_{PTCK}$	$t_{VPULSE}$ (s)	$Cycle_{VTCK}$
EPM7032S	4.02	342,000	0.03	200,000
EPM7064S	4.50	504,000	0.03	308,000
EPM7128S	5.11	832,000	0.03	528,000
EPM7160S	5.35	1,001,000	0.03	640,000
EPM7192S	5.71	1,192,000	0.03	764,000
EPM7256S	6.43	1,603,000	0.03	1,024,000

[Tables 7 and 8](#) show the in-system programming and stand alone verification times for several common test clock frequencies.

**Table 7. MAX 7000S In-System Programming Times for Different Test Clock Frequencies**

Device	$f_{TCK}$								Units
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	
EPM7032S	4.06	4.09	4.19	4.36	4.71	5.73	7.44	10.86	s
EPM7064S	4.55	4.60	4.76	5.01	5.51	7.02	9.54	14.58	s
EPM7128S	5.19	5.27	5.52	5.94	6.77	9.27	13.43	21.75	s
EPM7160S	5.45	5.55	5.85	6.35	7.35	10.35	15.36	25.37	s
EPM7192S	5.83	5.95	6.30	6.90	8.09	11.67	17.63	29.55	s
EPM7256S	6.59	6.75	7.23	8.03	9.64	14.45	22.46	38.49	s

**Table 8. MAX 7000S Stand-Alone Verification Times for Different Test Clock Frequencies**

Device	$f_{TCK}$								Units
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz	
EPM7032S	0.05	0.07	0.13	0.23	0.43	1.03	2.03	4.03	s
EPM7064S	0.06	0.09	0.18	0.34	0.64	1.57	3.11	6.19	s
EPM7128S	0.08	0.14	0.29	0.56	1.09	2.67	5.31	10.59	s
EPM7160S	0.09	0.16	0.35	0.67	1.31	3.23	6.43	12.83	s
EPM7192S	0.11	0.18	0.41	0.79	1.56	3.85	7.67	15.31	s
EPM7256S	0.13	0.24	0.54	1.06	2.08	5.15	10.27	20.51	s

## Programmable Speed/Power Control

MAX 7000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more, because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000 device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ , and  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters.

## Output Configuration

MAX 7000 device outputs can be programmed to meet a variety of system-level requirements.

### MultiVolt I/O Interface

MAX 7000 devices—except 44-pin devices—support the MultiVolt I/O interface feature, which allows MAX 7000 devices to interface with systems that have differing supply voltages. The 5.0-V devices in all packages can be set for 3.3-V or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

The VCCINT pins must always be connected to a 5.0-V power supply. With a 5.0-V VCCINT level, input voltage thresholds are at TTL levels, and are therefore compatible with both 3.3-V and 5.0-V inputs.

The VCCIO pins can be connected to either a 3.3-V or a 5.0-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 5.0-V supply, the output levels are compatible with 5.0-V systems. When VCCIO is connected to a 3.3-V supply, the output high is 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with VCCIO levels lower than 4.75 V incur a nominally greater timing delay of  $t_{OD2}$  instead of  $t_{OD1}$ .

### Open-Drain Output Option (MAX 7000S Devices Only)

MAX 7000S devices provide an optional open-drain (functionally equivalent to open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write enable signals) that can be asserted by any of several devices. It can also provide an additional wired-OR plane.



## IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 7000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. [Table 9](#) describes the JTAG instructions supported by the MAX 7000 family. The pin-out tables (see the Altera web site (<http://www.altera.com>) or the *Altera Digital Library* for pin-out information) show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

**Table 9. MAX 7000 JTAG Instructions**

JTAG Instruction	Devices	Description
SAMPLE/PRELOAD	EPM7128S EPM7160S EPM7192S EPM7256S	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
EXTEST	EPM7128S EPM7160S EPM7192S EPM7256S	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
ISP Instructions	EPM7032S EPM7064S EPM7128S EPM7160S EPM7192S EPM7256S	These instructions are used when programming MAX 7000S devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, BitBlaster download cable, or using a Jam File (.jam), Jam Byte-Code file (.jbc), or Serial Vector Format file (.svf) via an embedded processor or test equipment.

## Design Security

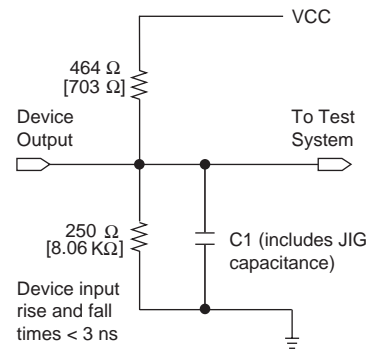
All MAX 7000 devices contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is reprogrammed.

## Generic Testing

Each MAX 7000 device is functionally tested. Complete testing of each programmable EEPROM bit and all internal logic elements ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in [Figure 10](#). Test patterns can be used and then erased during early stages of the production flow.

**Figure 10. MAX 7000 AC Test Conditions**

*Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V devices and outputs. Numbers without brackets are for 3.3-V devices and outputs.*



## QFP Carrier & Development Socket

MAX 7000 and MAX 7000E devices in QFP packages with 100 or more pins are shipped in special plastic carriers to protect the QFP leads. The carrier is used with a prototype development socket and special programming hardware available from Altera. This carrier technology makes it possible to program, test, erase, and reprogram a device without exposing the leads to mechanical stress.



For detailed information and carrier dimensions, refer to the [QFP Carrier & Development Socket Data Sheet](#).



MAX 7000S devices are not shipped in carriers.

Table 25. MAX 7000 & MAX 7000E External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-15		-15T		-20		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>SU</sub>	Global clock setup time		11.0		11.0		12.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input	(2)	3.0		–		5.0		ns
t <sub>FH</sub>	Global clock hold time of fast input	(2)	0.0		–		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		8.0		8.0		12.0	ns
t <sub>CH</sub>	Global clock high time		5.0		6.0		6.0		ns
t <sub>CL</sub>	Global clock low time		5.0		6.0		6.0		ns
t <sub>ASU</sub>	Array clock setup time		4.0		4.0		5.0		ns
t <sub>AH</sub>	Array clock hold time		4.0		4.0		5.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF		15.0		15.0		20.0	ns
t <sub>ACH</sub>	Array clock high time		6.0		6.5		8.0		ns
t <sub>ACL</sub>	Array clock low time		6.0		6.5		8.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	6.0		6.5		8.0		ns
t <sub>ODH</sub>	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		1.0		ns
t <sub>CNT</sub>	Minimum global clock period			13.0		13.0		16.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(5)	76.9		76.9		62.5		MHz
t <sub>ACNT</sub>	Minimum array clock period			13.0		13.0		16.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(5)	76.9		76.9		62.5		MHz
f <sub>MAX</sub>	Maximum clock frequency	(6)	100		83.3		83.3		MHz

**Table 26. MAX 7000 & MAX 7000E Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-15		-15T		-20		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			2.0		2.0		3.0	ns
$t_{IO}$	I/O input pad and buffer delay			2.0		2.0		3.0	ns
$t_{FIN}$	Fast input delay	(2)		2.0		—		4.0	ns
$t_{SEXP}$	Shared expander delay			8.0		10.0		9.0	ns
$t_{PEXP}$	Parallel expander delay			1.0		1.0		2.0	ns
$t_{LAD}$	Logic array delay			6.0		6.0		8.0	ns
$t_{LAC}$	Logic control array delay			6.0		6.0		8.0	ns
$t_{IOE}$	Internal output enable delay	(2)		3.0		—		4.0	ns
$t_{OD1}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 5.0\text{ V}$	$C1 = 35\text{ pF}$		4.0		4.0		5.0	ns
$t_{OD2}$	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$ (7)		5.0		—		6.0	ns
$t_{OD3}$	Output buffer and pad delay Slow slew rate = on $V_{CCIO} = 5.0\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$ (2)		8.0		—		9.0	ns
$t_{ZX1}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 5.0\text{ V}$	$C1 = 35\text{ pF}$		6.0		6.0		10.0	ns
$t_{ZX2}$	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$ (7)		7.0		—		11.0	ns
$t_{ZX3}$	Output buffer enable delay Slow slew rate = on $V_{CCIO} = 5.0\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$ (2)		10.0		—		14.0	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		6.0		6.0		10.0	ns
$t_{SU}$	Register setup time		4.0		4.0		4.0		ns
$t_H$	Register hold time		4.0		4.0		5.0		ns
$t_{FSU}$	Register setup time of fast input	(2)	2.0		—		4.0		ns
$t_{FH}$	Register hold time of fast input	(2)	2.0		—		3.0		ns
$t_{RD}$	Register delay			1.0		1.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.0		1.0		1.0	ns
$t_{IC}$	Array clock delay			6.0		6.0		8.0	ns
$t_{EN}$	Register enable time			6.0		6.0		8.0	ns
$t_{GLOB}$	Global control delay			1.0		1.0		3.0	ns
$t_{PRE}$	Register preset time			4.0		4.0		4.0	ns
$t_{CLR}$	Register clear time			4.0		4.0		4.0	ns
$t_{PIA}$	PIA delay			2.0		2.0		3.0	ns
$t_{LPA}$	Low-power adder	(8)		13.0		15.0		15.0	ns

**Table 28. EPM7032S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{PIA}$	PIA delay	(7)		1.1		1.1		1.4		1.0	ns
$t_{LPA}$	Low-power adder	(8)		12.0		10.0		10.0		11.0	ns

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3\text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in the low-power mode.

Tables 29 and 30 show the EPM7064S AC operating conditions.

**Table 29. EPM7064S External Timing Parameters (Part 1 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time		2.9		3.6		6.0		7.0		ns
t <sub>H</sub>	Global clock hold time		0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.5		0.5		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF		3.2		4.0		4.5		5.0	ns
t <sub>CH</sub>	Global clock high time		2.0		2.5		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		2.5		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time		0.7		0.9		3.0		2.0		ns
t <sub>AH</sub>	Array clock hold time		1.8		2.1		2.0		3.0		ns

**Table 30. EPM7064S Internal Timing Parameters (Part 2 of 2)** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-5		-6		-7		-10		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{FSU}$	Register setup time of fast input		1.9		1.8		3.0		3.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.7		0.5		0.5		ns
$t_{RD}$	Register delay			1.2		1.6		1.0		2.0	ns
$t_{COMB}$	Combinatorial delay			0.9		1.0		1.0		2.0	ns
$t_{IC}$	Array clock delay			2.7		3.3		3.0		5.0	ns
$t_{EN}$	Register enable time			2.6		3.2		3.0		5.0	ns
$t_{GLOB}$	Global control delay			1.6		1.9		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.0		2.4		2.0		3.0	ns
$t_{CLR}$	Register clear time			2.0		2.4		2.0		3.0	ns
$t_{PIA}$	PIA delay	(7)		1.1		1.3		1.0		1.0	ns
$t_{LPA}$	Low-power adder	(8)		12.0		11.0		10.0		11.0	ns

**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3\text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$  and  $t_{CPW}$  parameters for macrocells running in the low-power mode.

**Table 32. EPM7128S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade								Unit
			-6		-7		-10		-15		
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.2		0.5		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.2		0.5		0.5		2.0	ns
$t_{FIN}$	Fast input delay			2.6		1.0		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			3.7		4.0		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.1		0.8		0.8		1.0	ns
$t_{LAD}$	Logic array delay			3.0		3.0		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			3.0		3.0		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.7		2.0		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.4		2.0		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		0.9		2.5		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.4		7.0		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.0		3.0		2.0		4.0		ns
$t_H$	Register hold time		1.7		2.0		5.0		4.0		ns
$t_{FSU}$	Register setup time of fast input		1.9		3.0		3.0		2.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.5		0.5		1.0		ns
$t_{RD}$	Register delay			1.4		1.0		2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.0		1.0		2.0		1.0	ns
$t_{IC}$	Array clock delay			3.1		3.0		5.0		6.0	ns
$t_{EN}$	Register enable time			3.0		3.0		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.0		1.0		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.4		2.0		3.0		4.0	ns
$t_{CLR}$	Register clear time			2.4		2.0		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		1.4		1.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		11.0		10.0		11.0		13.0	ns

**Table 38. EPM7256S Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-7		-10		-15		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		2.0	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		2.0	ns
$t_{FIN}$	Fast input delay			3.4		1.0		2.0	ns
$t_{SEXP}$	Shared expander delay			3.9		5.0		8.0	ns
$t_{PEXP}$	Parallel expander delay			1.1		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.6		5.0		6.0	ns
$t_{LAC}$	Logic control array delay			2.6		5.0		6.0	ns
$t_{IOE}$	Internal output enable delay			0.8		2.0		3.0	ns
$t_{OD1}$	Output buffer and pad delay	C1 = 35 pF		0.5		1.5		4.0	ns
$t_{OD2}$	Output buffer and pad delay	C1 = 35 pF (6)		1.0		2.0		5.0	ns
$t_{OD3}$	Output buffer and pad delay	C1 = 35 pF		5.5		5.5		8.0	ns
$t_{ZX1}$	Output buffer enable delay	C1 = 35 pF		4.0		5.0		6.0	ns
$t_{ZX2}$	Output buffer enable delay	C1 = 35 pF (6)		4.5		5.5		7.0	ns
$t_{ZX3}$	Output buffer enable delay	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		5.0		6.0	ns
$t_{SU}$	Register setup time		1.1		2.0		4.0		ns
$t_H$	Register hold time		1.6		3.0		4.0		ns
$t_{FSU}$	Register setup time of fast input		2.4		3.0		2.0		ns
$t_{FH}$	Register hold time of fast input		0.6		0.5		1.0		ns
$t_{RD}$	Register delay			1.1		2.0		1.0	ns
$t_{COMB}$	Combinatorial delay			1.1		2.0		1.0	ns
$t_{IC}$	Array clock delay			2.9		5.0		6.0	ns
$t_{EN}$	Register enable time			2.6		5.0		6.0	ns
$t_{GLOB}$	Global control delay			2.8		1.0		1.0	ns
$t_{PRE}$	Register preset time			2.7		3.0		4.0	ns
$t_{CLR}$	Register clear time			2.7		3.0		4.0	ns
$t_{PIA}$	PIA delay	(7)		3.0		1.0		2.0	ns
$t_{LPA}$	Low-power adder	(8)		10.0		11.0		13.0	ns



**Notes to tables:**

- (1) These values are specified under the recommended operating conditions shown in [Table 14](#). See [Figure 13](#) for more information on switching waveforms.
- (2) This minimum pulse width for preset and clear applies for both global clear and array controls. The  $t_{LPA}$  parameter must be added to this minimum width if the clear or reset signal incorporates the  $t_{LAD}$  parameter into the signal path.
- (3) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (4) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) The  $f_{MAX}$  values represent the highest frequency for pipelined data.
- (6) Operating conditions:  $V_{CCIO} = 3.3\text{ V} \pm 10\%$  for commercial and industrial use.
- (7) For EPM7064S-5, EPM7064S-6, EPM7128S-6, EPM7160S-6, EPM7160S-7, EPM7192S-7, and EPM7256S-7 devices, these values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (8) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPTW}$  parameters for macrocells running in the low-power mode.

## Power Consumption

Supply power (P) versus frequency ( $f_{MAX}$  in MHz) for MAX 7000 devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The  $P_{IO}$  value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in [Application Note 74 \(Evaluating Power for Altera Devices\)](#).

The  $I_{CCINT}$  value, which depends on the switching frequency and the application logic, is calculated with the following equation:

$$I_{CCINT} =$$

$$A \times MC_{TON} + B \times (MC_{DEV} - MC_{TON}) + C \times MC_{USED} \times f_{MAX} \times \text{tog}_{LC}$$

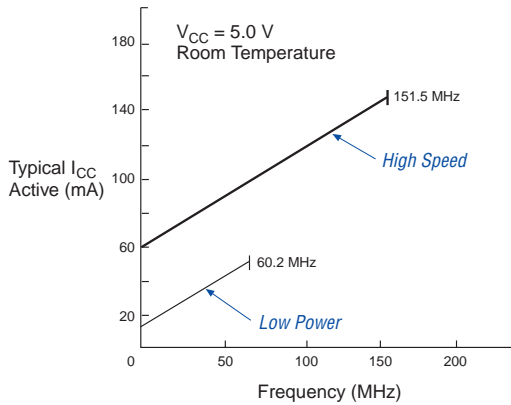
The parameters in this equation are shown below:

$MC_{TON}$	=	Number of macrocells with the Turbo Bit option turned on, as reported in the MAX+PLUS II Report File (.rpt)
$MC_{DEV}$	=	Number of macrocells in the device
$MC_{USED}$	=	Total number of macrocells in the design, as reported in the MAX+PLUS II Report File (.rpt)
$f_{MAX}$	=	Highest clock frequency to the device
$\text{tog}_{LC}$	=	Average ratio of logic cells toggling at each clock (typically 0.125)
A, B, C	=	Constants, shown in <a href="#">Table 39</a>

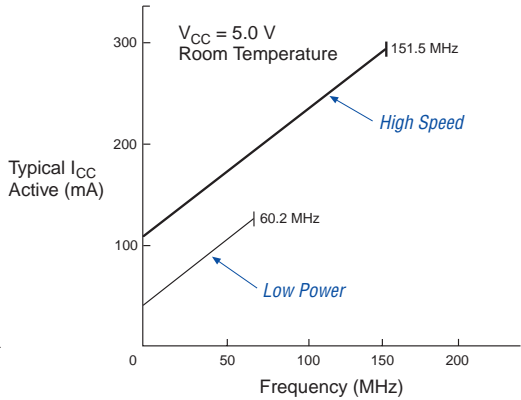
Figure 14 shows typical supply current versus frequency for MAX 7000 devices.

Figure 14.  $I_{CC}$  vs. Frequency for MAX 7000 Devices (Part 1 of 2)

EPM7032



EPM7064



EPM7096

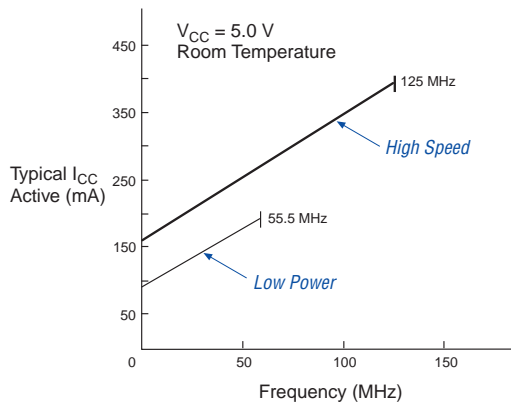
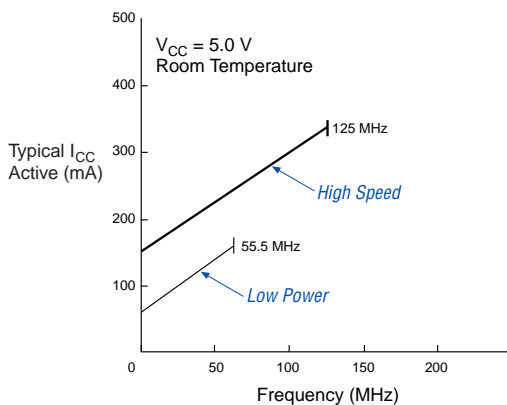
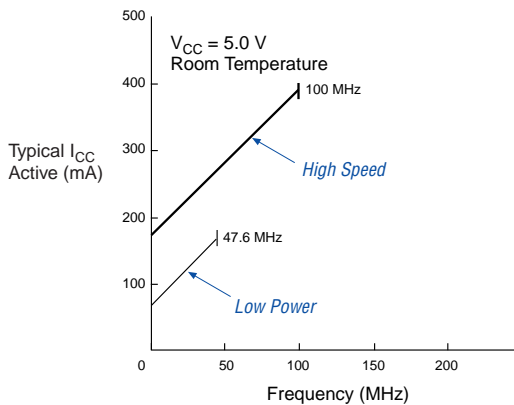


Figure 14.  $I_{CC}$  vs. Frequency for MAX 7000 Devices (Part 2 of 2)

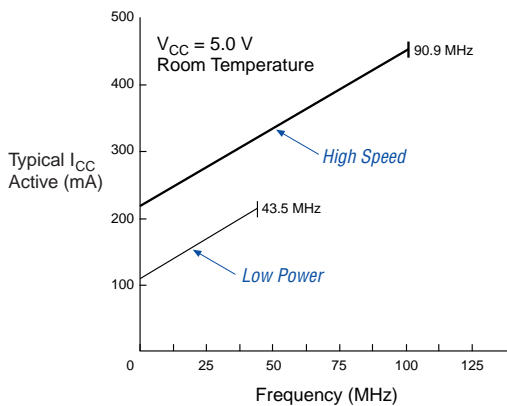
EPM7128E



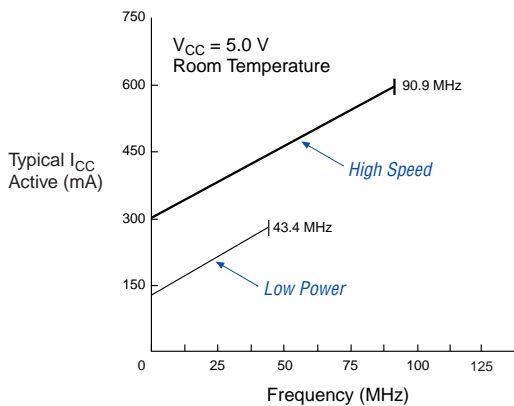
EPM7160E

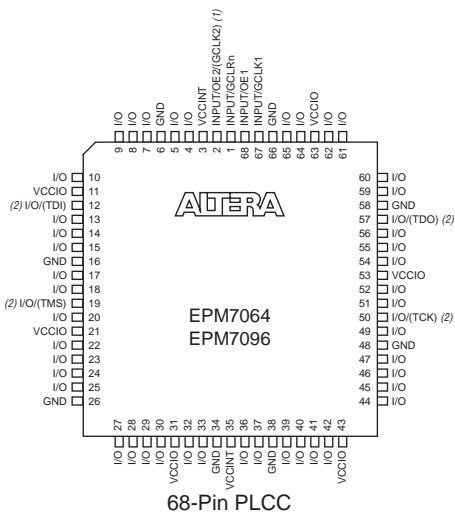


EPM7192E



EPM7256E

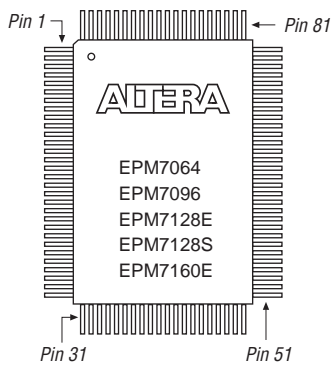


**Figure 17. 68-Pin Package Pin-Out Diagram***Package outlines not drawn to scale.***Notes:**

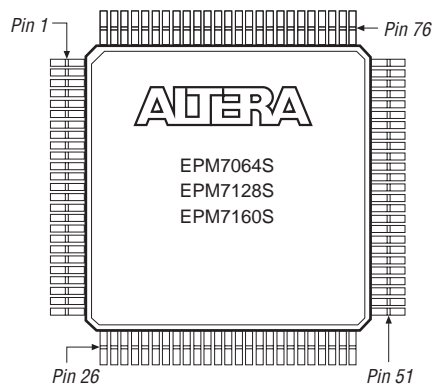
- (1) The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (2) JTAG ports are available in MAX 7000S devices only.

**Figure 19. 100-Pin Package Pin-Out Diagram**

*Package outline not drawn to scale.*



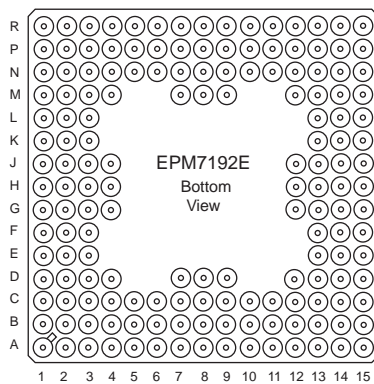
100-Pin PQFP



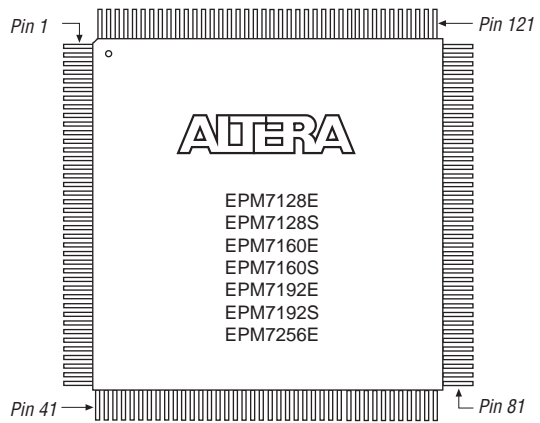
100-Pin TQFP

**Figure 20. 160-Pin Package Pin-Out Diagram**

*Package outline not drawn to scale.*



160-Pin PGA



160-Pin PQFP